



Accelerate Your Innovation and Discovery

See the latest technologies and trends in data acquisition, embedded control and monitoring and test. Join us for in-depth technical presentations, live product demonstrations and consultations with NI field engineers on your application needs. Register at ni.com/techroadshow.

Agenda

11:30 am–Noon: Registration

Noon–1:00 pm: Technical Session

1:00 pm–3:00 pm: Demo Showcase and Project Consultations

Technical Session: Top 3 Challenges of Developing a Measurement System

By design, the configuration-based model to take measurements is often the quickest way to get to initial results, but the long-term trade-offs may outweigh the early returns. In this session, explore measurement, control and test system challenges that often stretch the limits of configuration-based design. Learn the key considerations when configuring your next system to meet your application needs and minimize development time.

Featured Demonstrations:

- Data Acquisition using NI CompactDAQ and LabVIEW
- Embedded Control Monitoring using NI CompactRIO and LabVIEW
- Software Based Instrumentation using NI PXI and LabVIEW

Complimentary Project Consultations:

NI engineers will be on-site to discuss the latest technology advancements for solving your test, measurement, and embedded design challenges in your research applications and teaching labs. Take advantage of these experts being on your campus to get your questions answered.

Who Should Attend?

Researchers, professors and graduate students

University of Houston

Friday, March 27, 2015

Cullen College of Engineering 2, Room E312

Cost: Free

Register at ni.com/techroadshow

